

 <p>Substitute for form 1449/PTO</p> <p><b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b></p> <p>(Use as many sheets as necessary)</p>				<b>Complete if Known</b>	
				Application No.:	10/549,860
				Filing Date:	July 13, 2006
				First Named Inventor:	Nigel P. Smith
				Art Unit:	2811
				Examiner Name:	<del>Orin Nadeau</del> Jesse Miyoshi
Sheet	1	of	1	Attorney Docket No.:	NAN155 US 8027

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Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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	14.	International Search Report mailed on October 8, 2004 for PCT Application No. PCT/GB2004/001536 filed on April 8, 2004 by AOTI Operating Company, Inc., 6 pages.	
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Examiner Signature:	/Jesse Miyoshi/	Date Considered:	07/30/2009
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\* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.